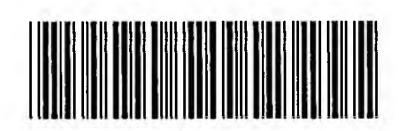
## Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

STEK ET AL.

Examiner

Art Unit

Huynh, Phuong

2857

SEARCHED				
Class	Subclass	Date	Examiner	
702 .	150	04/17/2007 .	PH	
73	865.9	04/18/2007	PH	
324	207.2; 207.25	04/18/2007	PH	
UPDATED	ABOVE	08/10/07	PH	
702	109-113, 116, 142-147,151-153, 163	08/10/2007	PH	
324	76.12,76.14	08/10/2007	PH	
UPDATED	ABOVE	08/12/2007	PH	
341	8,115	08/12/2007	PH	
324	207.12, 207.14; 76.13	08/12/2007	PH	

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with Primary Examiner Blane Jackson (AU 2618): no search in 455	04/18/2007	PH		
Consulted with Primary Examiner Thomas Noland: 73/865.9; 324/207.2,207.25	04/18/2007	PH		
702/150; 73/865.9; 324/207.2, 207.25 with text	04/18/2007	PH		
Assignment data (eDan)	04/18/2007	PH		
702/109-113, 116, 142-147,150-153, 163; 324/207.2; 207.25,76.12,76.14; 73/865.9 with text	08/10/2007	PH		
702/109-113, 116, 142-147,150-153, 163; 324/207.2; 207.12, 207.14, 207.25,76.12,76.13,76.14; 73/865.9; 341/8, 15 with text	8/12/2007	PH		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
702	112,113,145	08/12/2007	PH		
73	865.9	8/12/2007	PH		
341	8,115	8/12/2007	PH		
324	207.12; 76.13	8/12/2007	PH		

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